Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

#### description

logic symbol<sup>†</sup>

These devices contain six independent inverters. They perform the Boolean function  $Y = \overline{A}$  in positive logic. The open-drain outputs require pullup resistors to perform correctly. They may be connected to other open-drain outputs to implement active-low wired-OR or active-high wired-AND functions.

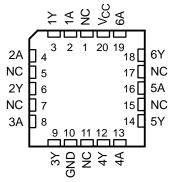
The SN54HC05 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C. The SN74HC05 is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

FUNCTION TABLE (each inverter)						
INPUT A	OUTPUT Y					
Н	L					
L	Н					

SN54HC05 ... J OR W PACKAGE SN74HC05 ... D OR N PACKAGE (TOP VIEW)

1A [	1	$\cup$	14	] V <sub>CC</sub> ] 6A
1Y [	2		13	] 6A
2A [				] 6Y
2Y [				] 5A
3A [				] 5Y
3Y [	6			] 4A
GND [	7		8	] 4Y

SN54HC05 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

1 A	1	1	$\Diamond$	2	1Y
1A	3	· ·	~	4	
2A	5			6	2Y
3A	9			8	3Y 4Y
4A	11			10	
5A	13			12	5Y
6A					6Y

<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, and W packages.

### logic diagram (positive logic)





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# SN54HC05, SN74HC05 **HEX INVERTERS** WITH OPEN-DRAIN OUTPUTS

SCLS080B - MARCH 1984 - REVISED MAY 1997

### absolute maximum ratings over operating free-air temperature range<sup>†</sup>

Supply voltage range, V <sub>CC</sub>	
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0 or V <sub>I</sub> > V <sub>CC</sub> ) (see Note 1)	±20 mA
Output clamp current, $I_{OK}$ (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> ) (see Note 1)	±20 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±25 mA
Continuous current through V <sub>CC</sub> or GND	±50 mA
Package thermal impedance, $\theta_{JA}$ (see Note 2): D package	127°C/W
N package	78°C/W
Storage temperature range, T <sub>stg</sub>	. –65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

#### recommended operating conditions

			S	N54HC0	5	SN74HC05			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		2	5	6	2	5	6	V
	$V_{CC} = 2 V$	1.5			1.5				
VIН	VIH High-level input voltage	$V_{CC} = 4.5 V$	3.15			3.15			V
		V <sub>CC</sub> = 6 V	4.2			4.2			
VIL Low-level input v		$V_{CC} = 2 V$	0		0.5	0		0.5	
	Low-level input voltage	V <sub>CC</sub> = 4.5 V	0		1.35	0		1.35	V
		VCC = 6 V	0		1.8	0		1.8	
VI	Input voltage		0		VCC	0		VCC	V
Vo	Output voltage		0		VCC	0		VCC	V
t <sub>t</sub> Input transition (rise and fall) time		$V_{CC} = 2 V$	0		1000	0		1000	
	Input transition (rise and fall) time	V <sub>CC</sub> = 4.5 V	0		500	0		500	ns
		VCC = 6 V	0		400	0		400	
ТА	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Vee	T	A = 25°C	;	SN54	HC05	SN74F	IC05	UNIT			
PARAWETER	TEST CC	INDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT			
IОН	$V_I = V_{IH} \text{ or } V_{IL},$	AO = ACC	6 V		0.01	0.5		10		5	μA			
	IOI		2 V		0.002	0.1		0.1		0.1				
		I <sub>OL</sub> = 20 μA	4.5 V		0.001	0.1		0.1		0.1				
VOL	$V_I = V_{IH} \text{ or } V_{IL}$		6 V		0.001	0.1		0.1		0.1	V			
		I <sub>OL</sub> = 4 mA	4.5 V		0.17	0.26		0.4		0.33				
					I <sub>OL</sub> = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
lı	$V_{I} = V_{CC} \text{ or } 0$		6 V		±0.1	±100		±1000		±1000	nA			
ICC	$V_{I} = V_{CC} \text{ or } 0,$	I <sup>O</sup> = 0	6 V			2		40		20	μA			
Ci			2 V to 6 V		3	10		10		10	pF			



# SN54HC05, SN74HC05 HEX INVERTERS WITH OPEN-DRAIN OUTPUTS

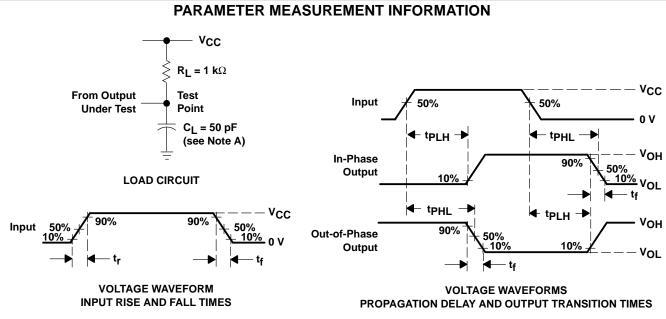
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#### switching characteristics over recommended operating free-air temperature range, CL = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vee	Τį	λ = 25°C	;	SN54	HC05	SN74	IC05	UNIT			
FARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT			
		Y	2 V		60	115		175		145				
<sup>t</sup> PLH	A		4.5 V		13	23		35		29	ns			
				6 V		10	20		30		25			
			2 V		45	85		130		105				
<sup>t</sup> PHL	A	Y	4.5 V		9	17		26		21	ns			
							6 V		8	14		22		18
			2 V		38	75		110		95				
tf	tf		Y	4.5 V		8	15		22		19	ns		
			6 V		6	13		19		16				

## operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per inverter	No load	20	pF



- NOTES: A. CL includes probe and test-fixture capacitance.
  - B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>r</sub> = 6 ns, t<sub>f</sub> = 6 ns.
  - C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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